

Substitute for form 1442/PTO		Complete if Known	
		Application Number	10/730,388
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Filing Date	December 07, 2003
		First Named Inventor	Buxton
		Art Unit	2863
		Examiner Name	KHUU, CINDY
Sheet 1	of 8	Attorney Docket Number	TAJ.0800

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
CME		APPLEWHITE. The view from the top. IEEE Spectrum, 41(11 (INT)):18-31, Nov 2004.	
CME		Canuto, M. Fairhurst and G. Howells, (2001) Improving ARTMap learning through variable vigilance. International Journal of Neural Systems, Vol. 11, No. 6, pp. 509-522.	
CME		Carpenter, G. A. and S. Grossberg, (1998) The ART of adaptive pattern recognition by self-organization neural network. Computer, vol. 21, no. 3, pp. 77-88.	
CME		K. Chang and J. Ghosh. Principal Curve Classifier - A nonlinear approach to pattern classification. In IEEE World Congress on Computational Intelligence, Neural... May1998	
CME		M. Clerc and J. Kennedy. The particle swarm - explosion, stability, and convergence in a multidimensional complex space. IEEE Transaction on Evolutionary Computation, Feb 2002	
CME		R. C. Eberhart and J. Kennedy, "A new optimizer using particle swarm theory", in Proc. 6th Intl. Symposium on Micro Machines and Human Science, Nagoya, Japan, IEEE 1995	
CME		R. C. Eberhart and Y. Shi. Evolving Artificial Neural Networks. In International Conference on Neural Networks and Brain, pages PL5 - PL13, Beijing, P.R. China, 1998	
CME		R. C. Eberhart and X. Hu, "Human Tremor analysis using particle swarm optimization", in Proc. Congress on Evolutionary Computation 1999, IEEE Service Center, pp 1927-1930	
CME		R.C. Eberhart and Y. Shi, "Comparing inertia weight and constriction factors in particle swarm optimization", in Proc. of the Congress of Evolutionary Computation, 2000	
CME		F. Chen and S. Liu, "A Neural-Network Approach To Recognize Defect Spatial Pattern in Semiconductor Fabrication", IEEE Transactions on Semiconductor Manufacturing, v.13 2000	

Examiner Signature	<i>Cindy Khuu</i>	Date Considered	1/23/07
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Substitute for form 1449/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet 2 of 8

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CML		T. Fountain, T. Dietterich, and B. Sudyka. Mining IC test data to optimize VLSI testing. the 6th ACM SIGKDD International Conference pages 18-25, 2000	
CML		N. Franken and A.P. Engelbrecht. Comparing PSO structures to learn the game of checkers from zero knowledge. In Congress on Evolutionary Computation, volume 1, Dec 2003	
CML		F. van den Bergh and A. P. Engelbrecht, "Cooperative Learning in Neural Networks using Particle Swarm Optimizers", South African Computer Journal, pp. 84-90, Nov. 2000	
CML		F. van den Bergh and A. P. Engelbrecht, "Training Product Unit Networks using Cooperative Particle Swarm Optimizers", In Proceedings of ICNN 2001, (Washington DC, USA), 2001	
		K. W. Tobin, S. S. Gleason, T. P. Karnowski, S. L. Cohen and F. Lakhani, Automatic Classification of Spatial Signatures on Semiconductor Wafermaps, SPIE 22nd Annual (1997)	
CML		S.S. Gleason, K.W. Tobin, T.P. Karnowski, and Fred Lakhani, (1999) Rapid Yield Learning through Optical Defect and Electrical Test Analysis, SPIE, 1999	
CML		Hu M. K. "Visual pattern recognition by moments invariants", IRE Transactions on Information Theory, Vol. 8(2), pp. 179-187, 1962	
CML		The National Technology Roadmap for Semiconductors, Semiconductor Industry Association, San Jose, 2001 (Executive Summary)	
CML		The National Technology Roadmap for Semiconductors, Semiconductor Industry Association, San Jose, 2001 (Test and Test Equipment)	
		K. Kameyama, and Y. Kosugi, "Semiconductor Defect Classification using Hyperellipsoid Clustering Neural Networks and Model Switching", Intl Joint Conf on Neural Networks 1999	

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		T.P. Kamowski, K.W. Tobin, S.S. Gleason, Fred Lakhani, "The Application of Spatial Signature Analysis to Electrical Test Data-Validation Study," SPIE 24th Ann'l Symp Feb 1999	
CML		J. Kennedy and R. Mendes. Population structure and particle swarm performance. In Congress on Evolutionary Computation, pages 1671-1676, 2002.	
CML		J. Kennedy and R. Mendes. Neighborhood topologies in fully-informed and best-of-neighborhood particle swarms. IEEE Int'l Workshop on Soft Computing Jul 2003	
CML		Kohonen T., The self-organizing map. Proceedings of the IEEE 78, pp. 1464-1480, 1990	
CML		Kveton and D. Dash. Automatic excursion detection in manufacturing: Preliminary results. 18th Int'l Florida Artificial Intelligence Research Conference May 2004	
CML		Lanzi, P. L., "Fast Feature Selection with Genetic Algorithms: A Filter Approach", IEEE International Conference on Evolutionary Computation, 13-16 April 1997, pp. 537-540	
CML		Leonardis and H. Bischof, "An efficient MDL-based construction of RBF networks", Neural Networks, vol. 11, pp963-973, 1998	
CML		Y. Liu, X. Yao and T. Higuchi, "Evolutionary Ensembles with Negative Correlation Learning", in IEEE Transactions on Evolutionary Computation, 4(4): 380-387, Nov. 2000	
CML		R. Mendes, J. Kennedy, and J. Neves. Watch thy neighbor or how the swarm can learn from its environment. IEEE Swarm Intelligence Symposium, pages 88 - 94, April 24-26 2003	
CML		R. Mendes, J. Kennedy, and J. Neves. The Fully Informed Particle: Simpler, Maybe Better. IEEE Transaction on Evolutionary Computation, 8:204-210, June 2004	

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CML		MIGUELANEZ, EMILIO, DIWA: Device Independent Wafermap Analysis, 2003	
CML		MIGUELANEZ, EMILIO, DIWA: Device Independent Wafermap Analysis, 2003 (PRESENTATION)	
CML		MIGUELANEZ, EMILIO, Automating the Analysis of Wafer Data Using Adaptive Resonance Theory Networks, 2004 (PRESENTATION)	
CML		MIGUELANEZ, EMILIO, Evolving Neural Networks using Swarm Intelligence for Binmap Classification, 2004	
CML		MIGUELANEZ, EMILIO, Automating the Analysis of Wafer Data Using Adaptive Resonance Theory Networks, 2004	
CML		MIGUELANEZ, EMILIO, Evolving Neural Networks using Swarm Intelligence for Binmap Classification, 2004 (PRESENTATION)	
CML		MIGUELANEZ, EMILIO, Swarm Intelligence in Automated Electrical Wafer Sort Classification, 2005	
WAP		T. Nakashima, G. Nakai, and H. Ishibuchi. Constructing fuzzy ensembles for pattern classification problems. IEEE Int'l Conf on Systems, Man and Cybernetics, October 2003.	
CML		Neblett. The role of test in total quality management. In Proceedings of the IEEE Systems Readiness Technology Conference AUTOTESTCON'94, volume I, pages 727-735, sep 1994	
CML		Ozcan and C.K. Mohan. Particle swarm optimization: Surfing the waves. In International Congress on Evolutionary Computation, pages 1939-1944, 1999	

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Sheet 5	of 8		

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CMK		K. E. Parsopoulos and M. N. Vrahatis. On the Computation of All Global Minimizers through Particle Swarm Optimization. IEEE Transaction on Evolutionary Computation, June 2004	
CMK		T. Poggio and F. Girosi, "Networks for approximation and learning", Proc. of the IEEE, vol. 78, pp1481-197, 1990	
CMK		J. Salerno, "Using the particle swarm optimization technique to train a recurrent neural model", IEEE Inter. Conference on Tools with Artificial Intelligence, pp 45-49, 1997	
CMK		Y. Shi and R.C. Eberhart, "Parameter selection in particle swarm optimization", in Proc. of the 1998 Annual Conference on Evolutionary Programming, San Diego, CA, 1998	
CMK		Y. Shi and R. C. Eberhart, "A Modified Particle Swarm Optimizer", in Proc. of Intl. Joint Conf. on Neural Networks, Washington, USA, pp. 69-73, July 1999	
CMK		K. W. Tobin, S. S. Gleason, T. P. Kamowski, An Image Paradigm for Semiconductor Defect Data Reduction, SPIE's International Symposium on Microlithography, 1996	
CMK		K.W. Tobin, S.S. Gleason, F. Lakhami, and M.H. Bennet, "Automated Analysis for Rapid Defect Sourcing and Yield Learning", Future Fab International, Vol. 4, 1997	
CMK		K.W. Tobin, S. S. Gleason, T.P. Kamowski, and S.L. Cohen, Feature Analysis and classification of Manufacturing Signatures on Semiconductor Wafers. SPIE 9th Annual, 1997	
CMK		K. W. Tobin, S. S. Gleason, T. P. Kamowski, S. L. Cohen and F. Lakhami, Automatic Classification of Spatial Signatures on Semiconductor Wafermaps, SPIE 22nd Annual, 1997	
CMK		Tseng, L. Y. and Yang, S. B., "Genetic Algorithms for Clustering, Feature Selection and Classification", International Conference on Neural Networks, 9-12 June 1997	

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Art Unit 2863

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CHU		Vafaie, H. and De Jong, K., "Genetic Algorithms as a Tool for Feature Selection in Machine Learning", 4th Int'l Conf on Tools with Artificial Intelligence, Nov. 1992	
CHU		Watkins and L. Boggess. A new classifier based on resource limited Artificial Immune Systems. In Congress on Evolutionary Computation CEC'02, vol II, pp 1546-51. IEEE May 2002	
CHU		C. Zhang, H. Shao, and Y. Li, "Particle swarm optimization for evolving artificial neural networks", IEEE Int'l Conf on Systems, Man and Cybernetics vol. 4, 2000	

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CKB		MADGE, ROBERT, et al. Statistical Post-Processing at Wafersort - An Alternative to Bum-in and a Manufacturable Solution to Test Limit Setting for Sub-Micron IEEE 2002	
CKB		MOTOROLA, Process Average Testing (PAT), Statistical Yield Analysis (SYA) and Junction Verification Test (JVT), Aug 03, 98	

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FOREIGN PATENT DOCUMENTS

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